



Substitute for form 1449-PTO		Complete if Known			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/020,961		
		Filing Date	December 19, 2001		
		First Named Inventor	Shunpei YAMAZAKI et al.		
		Art Unit	2812		
		Examiner Name	Stanetta D. Isaac		
Sheet	1	of	2	Attorney Docket Number	740756-2410

U.S. PATENT DOCUMENTS					
Examiner Initials [*]	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Signature	Stanetta Isaac	Date Considered	6/3/05
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Examiner Signature	<i>Stanetta Isaac</i>	Date Considered	6/03/05
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